1006-93-49 **X Alex Wang*** (`alex.wang@ttu.edu`), Department of Mathematics & Statistics, Texas Tech University, Lubbock, TX 79424-1042. *A Projective Metric of Linear Systems.*

To capture uncertainties, one needs a metric to measure the distance between nominal and perturbed systems. Since a linear system can be considered as a point in a projective space, a metric in projective space can be used naturally as a matric for linear systems. One major advantage of such a metric over the current known metrics is the simplicity of computation. (Received January 27, 2005)